Structural Phase Transition, Optical and Electrical Property Evolutions of Thiospinel AgIn₅S₈ under High Pressure

Ting Wen, Qian Zhang, Nana Li, Yonggang Wang, Dongzhou Zhang, Lin Wang, and Wenge Yang

†Center for High Pressure Science and Technology Advanced Research (HPSTAR), Beijing 100094, China
‡Hawaii Institute of Geophysics and Planetology, University of Hawaii Manoa, Honolulu, Hawaii, United States

ABSTRACT: Thiospinel AgIn₅S₈ as a visible-light-active semiconductor has been frequently used as a photoabsorber in solar cells, optoelectronics devices, and photovoltaic cells. Similar to temperature, pressure is an efficient external stimulus for both crystalline structural and electronic modulations to improve properties. Herein, we present the pressure tuning effect on AgIn₅S₈ up to 40 GPa. A pressure-driven phase transition from the ambient cubic spinel structure to an orthorhombic structure is observed around 10 GPa as evidenced from the in situ high pressure synchrotron X-ray diffraction results. The high pressure phase of AgIn₅S₈ adopts the defective LiVO₂-type structure with all the Ag⁺/In³⁺ cations sitting in the octahedrally coordinated environments. Both the electric transport and photocurrent measurements show dramatic changes along with the phase transition around 10 GPa, and the high pressure phase of AgIn₅S₈ exhibits greatly improved conductivity but decreased responses to visible light illumination. Surprisingly, the in situ UV−vis measurements reveal the onset pressure point of bandgap evolution around 7.5 GPa, far below the structural phase transition pressure around 10 GPa, which indicates the early initiated local structural change in the pressure range 7.5−10 GPa. An in situ Raman technique is used to confirm the coordination environment changes of AgIn₅S₈ under compression, the results of which reveal the coexistence of both the ambient and the high pressure structure features of AgIn₅S₈ in the pressure range 7.5−10 GPa. This work provides a demonstration on how external pressure affects the crystal structure, electronic structure, and optical properties of chalcogenide semiconductors and sheds light on the structure design of better optoelectrical materials under ambient conditions.

INTRODUCTION

Chalcogenides occur abundantly as minerals in nature and also have attracted intense scientific research attention as semiconducting materials in laboratories. They have been considered as advanced perspective semiconductors exhibiting a broad set of chemical and physical properties and involving a diverse variety of applications, including solar photovoltaics, thermoelectric materials, nonlinear optics, catalysis, electrochemical supercapacitors, superconductivity, etc. Additionally, chalcogenides are a chemical class next to organic compounds and metal oxides in compositional and structural diversity. The staggering variety offers us broad opportunities for learning structural insights and acquiring enhanced properties by structural modulations, such as dimensional reduction by chemical exfoliation, local structure distortion by doping, and phase homologies by governing the compositions. Besides the various well-demonstrated chemical strategies, pressure is also an efficient tool to tune the crystal and electronic structures by shortening interatomic distances and thus has promise to realize greatly improved physical properties. Many achievements in structural modulations and discovery of hidden phenomena have been acquired through high pressure techniques.  

Thiospinels, named after the prototype MgAl₂O₄, are a type of sulfide with the general formulation A⁺ᴵᴵᴮᴵᴵᴵᴵᴵᴵᴵ₊ₓXⅥ₋ₓ and crystallize in the cubic crystal system with space group Fd³m (no. 227). A partial degree of cation inversion is general in the spinel structure, which has aroused much research interest in the field of high-pressure science for the tunability of the antisite defects under compression. Additionally, the fact that phase transition is prone to occur in thiospinels under pressure has brought great attention, and the pressure-driven structural transition has also been studied extensively on compounds with a wide range of chemical compositions. Meanwhile, unusual phenomena such as metal−insulator transition and superconductor−insulator transition were also discovered in thiospinels under high pressure.

AgIn₅S₈ is one of thiospinel family and can be formulated in the general A⁺ᴵᴵᴮᴵᴵ查阅 the full text for the next section.
bandgap make it a potential photoabsorber in solar cells, optoelectronics devices, and photovoltaic-electrochemical cells.²⁰⁻²² So far, there is no scientific research report on AgIn₅S₈ under pressure, and its chemical and physical properties under high pressure are still unknown. In this study, we investigated the structural evolution and optical and electrical properties of AgIn₅S₈ under high pressure for the first time. Dramatic changes in the electric resistances and photocurrent performance of AgIn₅S₈ were observed and associated with the pressure-driven structural phase transition. We also observed abnormal bandgap changes as derived from the optical absorption measurements, which was discussed with the subtle local structure change under high pressure.

**EXPERIMENTAL SECTION**

**Material Synthesis.** AgIn₅S₈ was synthesized via a solvothermal route by using molten thiourea as the reactive flux. AgCl (0.1434 g, 1 mmol; 99.5%), InCl₃·H₂O (1.466 g, 5 mmol; 99.5%), and thiourea (SC(NH₂)₂; 2.284 g, 0.03 mol; AR) were weighed and ground together in an agate mortar for several minutes. The mixture was placed in a 50 mL Teflon-lined stainless-steel autoclave and heated at 220 °C for 10 h. An orange powder was obtained after the reaction and washed with ethanol several times. The reddish-brown powder was collected after drying at 80 °C overnight.

**Characterization.** The phase purity of the as obtained AgIn₅S₈ sample was checked with a Bruker D8 Advance diffractometer (Cu Kα source, λ = 0.154 nm) at room temperature and ambient pressure. The composition analysis was performed by energy-dispersive spectra (EDS) using a Quanta 250 FEG FEI Scanning Electron Microscope (SEM).

**In-Situ High-Pressure Characterizations.** Standard symmetrical diamond-anvil cells (DACs) with 300-µm culets were used in all high-pressure measurements. Stainless steel or rhenium gaskets were preindentated to about 40 µm in thickness, and 150 µm holes were drilled using a laser drilling system to serve as the sample chambers. The AgIn₅S₈ powder was pressed into a pellet and loaded into the sample chamber filled with silicone oil as the pressure-transmitting medium (PTM). A ruby sphere was then loaded to calibrate the pressure by using the ruby fluorescence method.²³ No PTM was used in the electrical transport measurements.

Powder X-ray diffraction (XRD) patterns were collected at beamline 13 BM-C at the Advanced Phonon Source (APS), Argonne National Laboratory (ANL). A focused monochromatic X-ray beam of about 12 µm × 18 µm in FWHM and a wavelength of 0.4340 Å was used. The diffraction data were recorded with a CCD image plate. High purity CeO₂ powder was used as the standard for calibration. The powder XRD patterns were integrated with the Dioptas program.²⁴ Lattice parameter refinements were performed by using the FULLPROF program.²⁵

Raman spectra were collected using a 532 nm line and a 2400 slits/mm diffraction grating in a Renishaw inVia spectrometer. UV–vis absorption spectrum measurements were conducted using an Ocean Optics QE65000 scientific-grade spectrometer. Transmittance data were recorded, and signals passing through the silicon oil area were used as a background. Resistance measurements were performed using the four-probe method with a 2182A nanovoltmeter, a Keithley 6221 current source, and a 7001 switch system. Photocurrent measurements were performed using a Zennium electrochemical workstation (Zahner) and a 50 W Xe lamp as the light illumination source.

**RESULTS AND DISCUSSION**

**Synthesis and Ambient Crystal Structure of AgIn₅S₈.**

AgIn₅S₈ powders were synthesized via a molten thiourea route.²⁰ The phase purity of the products was preliminarily confirmed by XRD (Figure S1) and energy-dispersive spectra (Figure S2) under ambient conditions. Rietveld refinement of the ambient XRD data was performed, and the result is plotted in Figure 1. The pattern can be well fitted by using the cubic space group Fd̅₃m (No. 227) with cell parameters a = b = c = 10.8303(2) Å. The crystal structure of AgIn₅S₈ is shown in the inset of Figure 1. Under ambient conditions, AgIn₅S₈ crystallizes in a normal spinel structure, which can be considered as a derivative of Cd(InₓS₄) with the Cd atom replaced by the Ag/In atom. From the view of structural chemistry, AgIn₅S₈ can also be noted as (Ag₀.₅In₀.₅)In₂S₄ to match the general formula of a spinel AₓB₄X₆. In such a structure, silver and 1/5 of the indium atoms locate disorderly in the tetrahedrally coordinated sites, and the other 4/5 of the indium atoms occupy the octahedrally coordinated positions. The (Ag/In)S₄ tetrahedra and the InS₆ octahedra connect each other in a corner-sharing manner.

**Pressure-Induced Phase Transition.** To explore the structure evolution of AgIn₅S₈ under high pressure, in situ powder XRD measurements were conducted up to 42.3 GPa. Figure 2 shows the XRD patterns of AgIn₅S₈ as a function of pressure.

![Figure 1. Rietveld refinement plot of AgIn₅S₈ at room temperature in space group Fd̅₃m, a = b = c = 10.8303(2) Å. Green circles: experimental data. Red line: calculated. Green bars: Bragg reflection positions. Gray line: difference. Inset shows the crystal structure of AgIn₅S₈ under ambient conditions comprised of (Ag/In)S₄ tetrahedra (gray) and InS₆ octahedra (blue).](image)

![Figure 2. Powder XRD patterns of AgIn₅S₈ as a function of pressure.](image)
pressure. At ambient pressure and below 10.5 GPa, all the peaks can be well indexed with the cubic space group $Fd\bar{3}m$. As the pressure increases, most of the diffraction peaks shift to higher 2$\theta$ values, indicating the contraction of the unit cell and a decrease of the interatomic distances under compression. A structural phase transition occurs at 10.5 GPa as a set of new peaks emerge, and the high pressure (HP) phase can be preserved up to 42.3 GPa. Moreover, the pressure-induced phase transition of AgIn$_5$S$_8$ around 10.5 GPa is reversible. After pressure releasing, AgIn$_5$S$_8$ returns to the original spinel structure (Figure S3).

We found that the XRD pattern of the HP phase of AgIn$_5$S$_8$ can match that of LiVO$_2$($Fd\bar{3}m$) well (Figure S4). The difference between the formulas of LiVO$_2$($A^I B^{II} X^{VI}$) and the spinel (Ag$_{0.9}$In$_{0.1}$)In$_2$S$_4$ ($A^{II} B^{III} X^{VI}$) can be made up by taking the existence of vacancies into account in a chemical formula $[(A_{0.9}In_{0.1})\square]In_2S_4$. Thus, a defective LiVO$_2$-type structure with orthorhombic space group $Imma$ (No. 74) is adopted for the structure refinements of the HP-AgIn$_5$S$_8$.14,27 Figure 3b shows the representative powder XRD reference X-ray diffraction patterns of AgIn$_5$S$_8$ at selected pressures: (a) 8.5 GPa and (b) 11.6 GPa. The observed, calculated, and difference X-ray diffraction profiles are represented as cyan/blue, red, and gray lines, respectively.

Figure 3. Rietveld refinement results based on the powder XRD data of AgIn$_5$S$_8$ at selected pressures: (a) 8.5 GPa and (b) 11.6 GPa. The structural phase transition occurs around 10.5 GPa with a discontinuousness in the cell parameters. The LP to HP phase transition in AgIn$_5$S$_8$ accompanies a volume decrease by 2.9%, indicating a little more closely packed defective LiVO$_2$ structure. The P–V data were used to fit the equation of state (EOS) using a third-order Birch–Murnaghan method.28 The results show that the HP phase of AgIn$_5$S$_8$ ($B_0 = 126$ GPa) is harder to compress than the LP phase of AgIn$_5$S$_8$ ($B_0 = 97$ GPa).

**Transport and Optical Properties of AgIn$_5$S$_8$ under High Pressure.** The electrical conductivity and photocurrent are two important characteristics of a semiconductor for practical applications. In situ resistance measurement of AgIn$_5$S$_8$ was carried out by using four-probe methods within DAC devices to explore the transport behavior of AgIn$_5$S$_8$ under high pressure. In situ photocurrent was measured using the same setup with Xe light as the light illumination source. Both the resistance and photocurrent are not detected before 7 GPa due to high contact resistance between the Au wires and the powder. Figure 6a shows the electrical resistance as a function of pressure in the range of 7−34.1 GPa. Along with
the pressure increase, the electric resistance falls down in the whole measured pressure range by 6 orders of magnitude and drops quickly at approximately 10 GPa, coinciding with the structural phase transition pressure. The temperature dependence of resistance was measured at different pressures for the HP phase of AgIn$_5$S$_8$ (as shown in Figure 6b), from which typical semiconductor behavior for the HP phase of AgIn$_5$S$_8$ is evident. In the photocurrent measurements (as shown in Figure 7), AgIn$_5$S$_8$ shows an obvious response to the on−off switch of the visible light in both the LP and HP phases. The photocurrent intensity falls down dramatically by 3 orders of magnitude from 7 to 10.8 GPa and then decreases slowly up to 34.1 GPa. The evolutions of both the transport and photocurrent intensity are obviously caused by the crystal structure change with the pressure-induced phase transition around 10 GPa.

Bandgap is another important characteristic for a chalcogenide semiconductor. The bandgap evolution of AgIn$_5$S$_8$ is derived from the optical absorbance data by using the Tauc plot method,
\begin{equation}
(h\nu/\alpha)^1/n = A(h\nu - E_g)
\end{equation}
where \(h\) is Planck’s constant, \(\nu\) is the frequency of vibration, \(\alpha\) is the absorption coefficient, \(E_g\) is the bandgap, and \(A\) is the proportional constant. The value of the exponent \(n\) denotes the nature of the sample transition and is theoretically equal to 1/2 or 2 for direct allowed and indirect allowed transitions, respectively.

AgIn$_5$S$_8$ is a direct bandgap semiconductor despite some debate in previous studies.\textsuperscript{31−35} In our study, the optical absorption spectra of AgIn$_5$S$_8$ at low pressures exhibit a steep absorption, which also confirms the characteristic of a direct bandgap (Figure 8a and b). Thus, \(n = 1/2\) is used for the fitting of the absorbance data to obtain the bandgap values of AgIn$_5$S$_8$ up to 7.5 GPa. However, the absorption spectra above 8.5 GPa tend to be flat, which is obviously different from the shape at lower pressures. This suggests a direct-to-indirect bandgap transition in AgIn$_5$S$_8$ along with the structural phase transition under compression. So, \(n = 2\) is chosen to obtain the indirect bandgap values from 8.5 to 13.7 GPa. As shown in Figure 8c, the bandgap value (\(E_g\)) of AgIn$_5$S$_8$ increases linearly upon compression up to 6.9 GPa and decreases sharply from 7.5 to 9.6 GPa, followed by a linear decrease above 10.6 GPa. The bandgap evolution of AgIn$_5$S$_8$ is inconsistent with the structural phase transition, indicating an early initiated subtle local structure change between 7.5 and 10.6 GPa. Moreover, the bandgap change of AgIn$_5$S$_8$ under high pressure is reversible upon pressure release.

**Raman Spectra of AgIn$_5$S$_8$ under High Pressure.**
Raman spectroscopy was used to gain further insight into the local structure change of AgIn$_5$S$_8$ under high pressure. Figure 9 represents the room temperature Raman spectra of AgIn$_5$S$_8$ up to 40.5 GPa. At 0.6 GPa, four peaks at wavenumbers 180, 281, 330, and 360 cm$^{-1}$ are observed, which can be assigned to the vibration modes of $E_g$, $F_{2g}^2$, $F_{2g}^3$, and $A_{1g}$ of (Ag/In)S$_4$ tetrahedra.\textsuperscript{19} Then, all the Raman peaks shift to higher wavenumbers and the peak intensity increases at the same time up to 7.5 GPa, which can be attributed to the shortening of the (Ag/In)−S bond length under compression. Starting from 8.4 GPa, the Raman intensities, take the $F_{2g}^3$ mode for example, decrease sharply (as shown in Figure 9c). This indicates the starting of tetrahedrally coordinated Ag/In ions migrating to the interstitial sites in the spinel structure. This also marks the
beginning of the phase transition to defective LiVO$_2$-type structure and supports the previous structural analysis results well. Notably, one can consider a coexistence of the LP and HP phases in a pressure range from 8.4 to 9.5 GPa, and the structural phase transformation completes at 10.4 GPa. The local structure evolution as evidenced from the Raman spectra is consistent with the observation of the transitional range between 7.5 and 10.6 GPa from the bandgap data. This is a good demonstration for Raman spectra as a powerful tool to capture subtle local structure changes that are difficult to catch by diffraction techniques. Above 10.4 GPa, no other Raman change has been observed, indicating that the defective LiVO$_2$-type structure of AgIn$_5$S$_8$ can be kept up to 40 GPa. Indeed, in a stoichiometric LiVO$_2$ structure, Raman peaks are not expected for ideal (Ag/In)$_6$ or In$_6$ octahedra. The emerging broad band with two maxima (denoted as R1, R2) suggests the symmetry breakdown and the existence of vacancies in the octahedrally coordinated sites.$^{15}$

**CONCLUSIONS**

In summary, we report the pressure modulating of structural, optical, and electrical properties of AgIn$_5$S$_8$ up to 40 GPa. The in situ powder XRD measurements indicate a structural phase transition around 10.5 GPa from cubic spinel structure to a defective LiVO$_2$ structure with space group $Imma$. Electrical transport and photocurrent behavior of AgIn$_5$S$_8$ show dramatic changes around 10 GPa, consistent with the pressure-induced structural phase transition. The bandgap values derived from the absorption data show abnormal changes around 7.5 GPa, which indicates a possible direct-to-indirect bandgap transition and a subtle local structure change starting from 7.5 GPa. Raman spectra confirm the early initial local structural evolution and the mixed structural features in a pressure range between 7.5 and 10.4 GPa. Studies on chalcogenide semiconductors under external pressure can provide in-depth understanding of the structure–property relationship and shed light on the structure design of better optoelectrical materials under ambient conditions.

**ASSOCIATED CONTENT**

*Supporting Information*

The Supporting Information is available free of charge on the ACS Publications website at DOI: 10.1021/acs.inorg-chem.9b01351.

Figures S1–S4 showing the XRD, the EDS of an ambient AgIn$_5$S$_8$ sample, a comparison of XRD patterns of AgIn$_5$S$_8$ released from high pressure compression to ambient pressure and the initial sample before compression, and the XRD comparison between HP-AgIn$_5$S$_8$ and LiVO$_2$ (PDF)

**AUTHOR INFORMATION**

*Corresponding Authors*

*E-mail: yonggang.wang@hpstar.ac.cn.*

*E-mail: yangwg@hpstar.ac.cn.*
ACKNOWLEDGMENTS

This work was supported by the National Key R&D Program of China (2018YFA0305900) and National Natural Science Foundation of China (51527801 and U1530402). GeoSoilEnviroCARS is supported by the National Science Foundation-Earth Sciences (EAR-1634415) and Department of Energy-GeoSciences (DE-FG02-94ER14466). The PX2 program is supported by COMPres under NSF Cooperative Agreement EAR-1661511. APS is supported by DOE-BES, under contract No. DE-AC02-06CH11357.

REFERENCES